Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/802,885	MURATA ET AL.
Examiner	Art Unit
Thomas J. Magee	2811

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Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	STRATEGY) DATE EXMR		
used EKIT for class/ subclass search: USIKI, PGPUB, EPO; UPO, DELLWENT	419105		
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